

The **MicroINSPECT** wafer inspection system integrates more applications with ergonomic ease of operation. A small footprint, high speed, low cost per feature and serviceability contribute to its' award winning CoO\*.



**SITEview™ Applications Include:**

- ▶ Visual Inspection
- ▶ Defect Review
- ▶ OCR
- ▶ Sorting
- ▶ Second Optical Inspection
- ▶ Image Storage & Retrieval
- ▶ Overlay Measurement
- ▶ Laser Marking
- ▶ GEM/SECS II
- ▶ Host Communication – LAN
- ▶ UV Microscope Interface
- ▶ 50mm – 300mm Wafers
- ▶ 1 to 4 Cassette Towers
- ▶ Motorized Tilt Back w/ or w/out Integrated Flat/Notch Aligner
- ▶ Multi-Cassette Size Auto Recognition
- ▶ OCR
- ▶ Cassette BCR
- ▶ Laser Marker compatible
- ▶ 20" Hi Res Flat Panel Display
- ▶ Integrate **EAGLEview™** module

**Custom Configurations:**

- ▶ Integrate to any microscope or existing microscopes
- ▶ Confocal UV Optics
- ▶ Stepper or Hi Speed DC Robots & Stages
- ▶ Hi – Accuracy Stage
- ▶ Mini Environment Enclosure

**Easy Robot Setup – Detailed Diagnostics**

- ▶ Easy to use GUI service interface simplifies diagnostics and provides an automated robot teach routine for each wafer exchange position.
- ▶ **SITEview™** provides an easy upgrade path for existing LEP MAC 2000 based systems

\*Lucent - Vendor of the Year Award- lowest CoO worldwide - '97, '98, '99